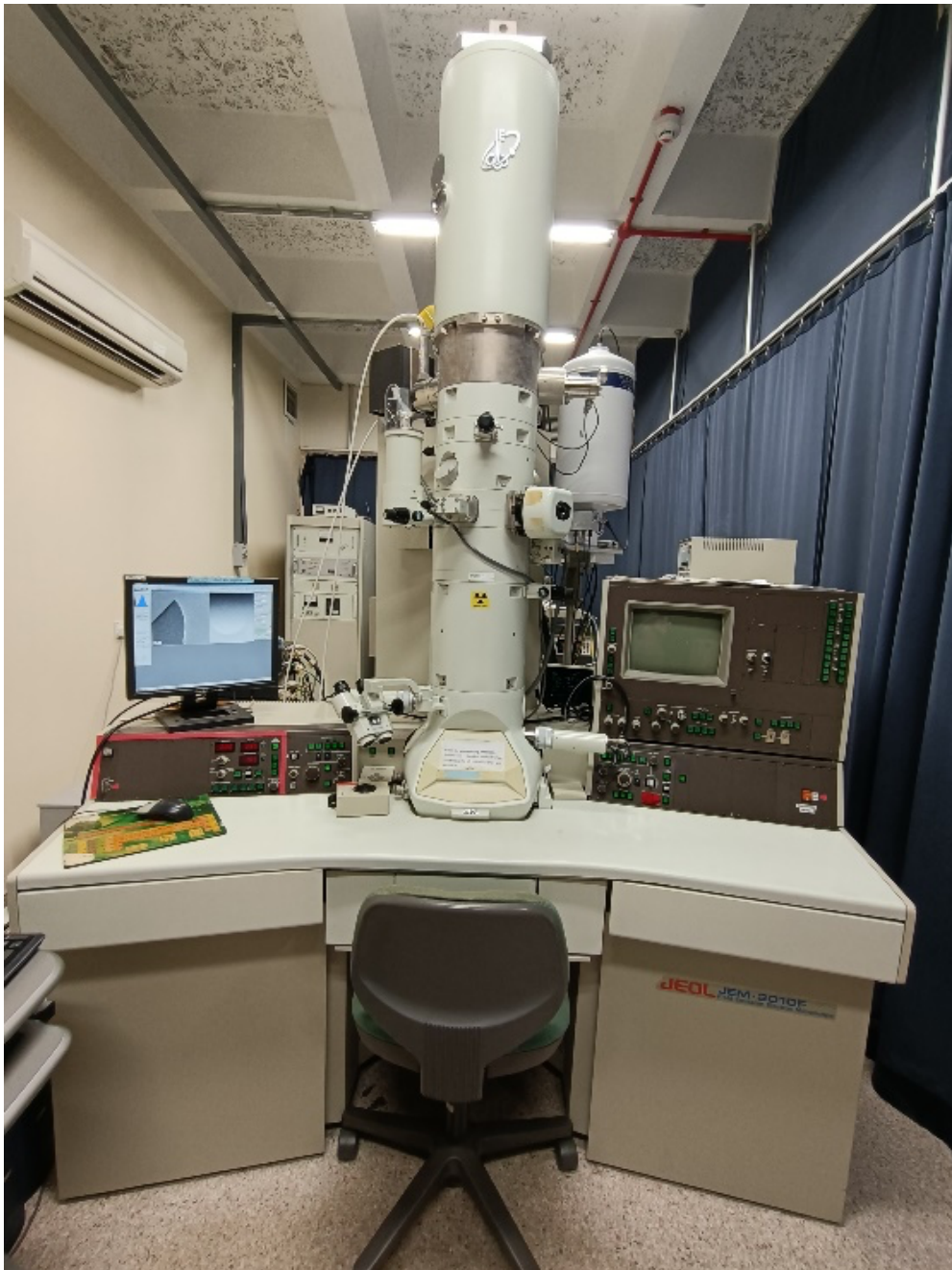


## JEOL JEM-2010F Field Emission Electron Microscope



The JEM-2010F Field Emission Electron Microscope has been developed to obtain the highest image quality and analytical performance as a 200kV class analytical TEM. It employs a field emission gun (FEG), provided with an electron source having high brightness, high coherency and narrow energy spread. It is also equipped with scanning transmission microscope and Oxford energy dispersive X-ray spectroscopy allowing microarea element analysis.